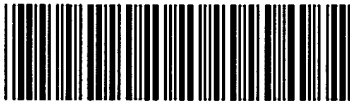


**Search Notes**

Application/Control No.

10/533,556

Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

PARK, JOON-YOUNG

Art Unit

2831

**SEARCHED**

Class	Subclass	Date	Examiner
174	135	12/12/2005	LEE
361	220	//	//
174	5, 5sg, 6	5/30/2006	LEE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
174	as above	12/12/2005	LEE
361	as above	12/12/2005	LEE
174	as above	5/30/2006	LEE

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search attached	12/12/2005	LEE
East text search attached	5/30/2006	LEE